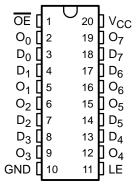
- **Function and Pinout Compatible With FCT** and F Logic
- Reduced V_{OH} (Typically = 3.3 V) Versions of Equivalent FCT Functions
- **Edge-Rate Control Circuitry for** Significantly Improved Noise Characteristics
- I_{off} Supports Partial-Power-Down Mode Operation
- **ESD Protection Exceeds JESD 22**
 - 2000-V Human-Body Model (A114-A)
 - 200-V Machine Model (A115-A)
 - 1000-V Charged-Device Model (C101)
- **Matched Rise and Fall Times**
- Fully Compatible With TTL Input and **Output Logic Levels**
- **3-State Outputs**
- CY54FCT373T
 - 32-mA Output Sink Current
 - 12-mA Output Source Current
- CY74FCT373T
 - 64-mA Output Sink Current
 - 32-mA Output Source Current

CY54FCT373T . . . D PACKAGE CY74FCT373T...Q OR SO PACKAGE (TOP VIEW)



description

The 'FCT373T devices consist of eight latches with 3-state outputs for bus-organized applications. When the latch-enable (LE) input is high, the flip-flops appear transparent to the data. Data that meets the required setup times are latched when LE transitions from high to low. Data appears on the bus when the output-enable $(\overline{\sf OE})$ input is low. When $\overline{\text{OE}}$ is high, the bus output is in the high-impedance state. In this mode, data can be entered into the latches.

These devices are fully specified for partial-power-down applications using Ioff. The Ioff circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



ORDERING INFORMATION

TA	PACKAGET		SPEED (ns)	ORDERABLE PART NUMBER	TOP-SIDE MARKING	
	QSOP - Q	Tape and reel	4.7	CY74FCT373CTQCT	FCT373C	
	SOIC - SO	Tube	4.7	CY74FCT373CTSOC	FCT373C	
	3010 = 30	Tape and reel	4.7	CY74FCT373CTSOCT	FC1373C	
-40°C to 85°C	QSOP – Q	Tape and reel	5.2	CY74FCT373ATQCT	FCT373A	
-40 C to 65 C	SOIC - SO	Tube 5.2 CY74FCT373ATSOC		CY74FCT373ATSOC	FCT373	
	3010 = 30	Tape and reel	5.2	CY74FCT373ATSOCT	15013/3	
	SOIC - SO	Tube	8	CY74FCT373TSOC	FCT373	
	3010 - 30	Tape and reel	8	CY74FCT373TSOCT	FC13/3	
–55°C to 125°C	CDIP – D	Tube	5.6	CY54FCT373ATDMB		

[†] Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

FUNCTION TABLE

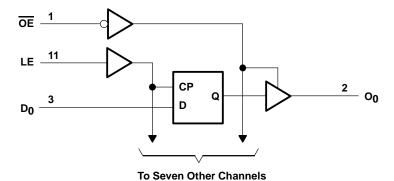
	INPUTS	OUTPUT	
OE	LE	D	0
L	Н	Н	Н
L	Н	L	L
L	L	Χ	Q_0
Н	X	Χ	z

H = High logic level, L = Low logic level,

X = Don't care, Z = High-impedance state,

 Q_n = Previous state of flip flops (Q_{n-1})

logic diagram (positive logic)





absolute maximum rating over operating free-air temperature range (unless otherwise noted)†

Supply voltage range to ground potential	0.5 V to 7 V
DC input voltage range	-0.5 V to 7 V
DC output voltage range	$-0.5\ V$ to 7 V
DC output current (maximum sink current/pin)	120 mA
Package thermal impedance, θ _{JA} (see Note 1): Q package	68°C/W
SO package	58°C/W
Ambient temperature range with power applied, T _A	-65° C to 135° C
Storage temperature range, T _{stq}	65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions (see Note 2)

		CY54FCT373T			CY7	UNIT		
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
VIH	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.8			0.8	V
ІОН	High-level output current			-12			-32	mA
loL	Low-level output current			32			64	mA
T _A	Operating free-air temperature	-55		125	-40		85	°C

NOTE 2: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation.



NOTE 1: The package thermal impedance is calculated in accordance with JESD 51-7.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETER	TEST CONDITIONS			CY	54FCT37	73T	CY	74FCT37	'3T	LINIT	
PARAMETER		TEST CONDITIO	ONS	MIN	TYP [†]	MAX	MIN	TYP [†]	MAX	UNIT	
Voc	V _{CC} = 4.5 V,	I _{IN} = -18 mA			-0.7	-1.2				V	
VIK	$V_{CC} = 4.75 \text{ V},$	I _{IN} = -18 mA						-0.7	-1.2	V	
	$V_{CC} = 4.5 \text{ V},$	$I_{OH} = -12 \text{ mA}$		2.4	3.3						
Voн	V _{CC} = 4.75 V	$I_{OH} = -32 \text{ mA}$					2			V	
	VCC = 4.75 V	$I_{OH} = -15 \text{ mA}$					2.4	3.3			
Voi	$V_{CC} = 4.5 \text{ V},$	I_{OL} = 32 mA			0.3	0.55				V	
VOL	$V_{CC} = 4.75 \text{ V},$	$I_{OL} = 64 \text{ mA}$						0.3	0.55	V	
V_{hys}	All inputs				0.2			0.2		V	
١,	$V_{CC} = 5.5 \text{ V},$	VIN = VCC				5				μΑ	
'1	$V_{CC} = 5.25 \text{ V},$	VIN = VCC							5	μΛ	
l	$V_{CC} = 5.5 \text{ V},$	$V_{1N} = 2.7 \text{ V}$				±1				μΑ	
ΊΗ	$V_{CC} = 5.25 \text{ V},$	V _{IN} = 2.7 V							±1	μΛ	
IIL	$V_{CC} = 5.5 \text{ V},$	V _{IN} = 0.5 V				±1				μΑ	
'IL	$V_{CC} = 5.25 \text{ V},$	V _{IN} = 0.5 V							±1	μΛ	
IOZH	$V_{CC} = 5.5 \text{ V},$	V _{OUT} = 2.7 V				10				μΑ	
10ZH	$V_{CC} = 5.25 \text{ V},$	V _{OUT} = 2.7 V							10	μΛ	
IOZL	$V_{CC} = 5.5 \text{ V},$	V _{OUT} = 0.5 V				-10				μΑ	
'OZL	$V_{CC} = 5.25 \text{ V},$	V _{OUT} = 0.5 V							-10	μι	
los‡	$V_{CC} = 5.5 \text{ V},$	$V_{OUT} = 0 V$		-60	-120	-225				mA	
105+	$V_{CC} = 5.25 \text{ V},$	V _{OUT} = 0 V					-60	-120	-225	ША	
l _{off}	$V_{CC} = 0 V$,					±1			±1	μΑ	
Icc	$V_{CC} = 5.5 \text{ V},$	$V_{IN} \le 0.2 V$	$V_{IN} \ge V_{CC} - 0.2 \text{ V}$		0.1	0.2				mΑ	
'00			$V_{IN} \ge V_{CC} - 0.2 \text{ V}$					0.1	0.2	111/5	
ΔlCC		$_{\text{N}} = 3.4 \text{ V}$, $f_1 = 0$, Ou			0.5	2				mA	
۵۱٫۲۲	$V_{CC} = 5.25 \text{ V, V}$	$IN = 3.4 \text{ V}$, $f_1 = 0$, C	Outputs open					0.5	2	ША	

[†] Typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.



Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high-speed test apparatus and/or sample-and-hold techniques are preferable to minimize internal chip heating and more accurately reflect operational values. Otherwise, prolonged shorting of a high output can raise the chip temperature well above normal and cause invalid readings in other parametric tests. In any sequence of parameter tests, IOS tests should be performed last.

[§] Per TTL-driven input (V_{IN} = 3.4 V); all other inputs at V_{CC} or GND

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted) (continued)

DADAMETED		TEST CONDITION	10	CY	54FCT3	73T	CY	74FCT37	'3T	LINUT	
PARAMETER	TEST CONDITIONS			MIN	TYP [†]	MAX	MIN	TYP [†]	MAX	UNIT	
loop¶		tputs open, iing at 50% duty cycle, IN ≥ V _{CC} – 0.2 V	OE = GND,		0.06	0.12				mA/	
ICCD¶	V_{CC} = 5.25 V, Outputs open, One input switching at 50% duty cycle, \overline{OE} = GND, $V_{IN} \le 0.2 \text{ V or } V_{IN} \ge V_{CC} - 0.2 \text{ V}$							0.06	0.12	MHz	
	V _{CC} = 5.5 V,	One bit switching at f ₁ = 10 MHz	$V_{IN} \le 0.2 \text{ V or}$ $V_{IN} \ge V_{CC} - 0.2 \text{ V}$		0.7	1.4					
	Outputs open, OE = GND, LE = VCC	at 50% duty cycle	$V_{IN} = 3.4 \text{ V or GND}$		1	2.4					
		1 - V - V	Eight bits switching at f ₁ = 2.5 MHz	$V_{IN} \le 0.2 \text{ V or}$ $V_{IN} \ge V_{CC} - 0.2 \text{ V}$		1.3	2.6				
lc#		at 50% duty cycle	$V_{IN} = 3.4 \text{ V or GND}$		3.3	10.6				mA	
ıC		One bit switching at f ₁ = 10 MHz	$V_{IN} \le 0.2 \text{ V or}$ $V_{IN} \ge V_{CC} - 0.2 \text{ V}$					0.7	1.4	IIIA	
	V _{CC} = 5.25 V, Outputs open,	at 50% duty cycle	$V_{IN} = 3.4 \text{ V or GND}$					1	2.4		
	OE = GND, LE = V _{CC}	' LIUITI DILE SWILCHING I	$V_{IN} \le 0.2 \text{ V or}$ $V_{IN} \ge V_{CC} - 0.2 \text{ V}$					1.3	2.6		
		at 50% duty cycle	V _{IN} = 3.4 V or GND					3.3	10.6		
C _i					6	10		6	10	pF	
Co					8	12		8	12	pF	

[†] Typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

Where:

 $\begin{array}{ll} I_C & = \mbox{Total supply current} \\ I_{CC} & = \mbox{Power-supply current with CMOS input levels} \end{array}$

 ΔI_{CC} = Power-supply current for a TTL high input ($V_{IN} = 3.4 \text{ V}$)

D_H = Duty cycle for TTL inputs high N_T = Number of TTL inputs at D_H

I_{CCD} = Dynamic current caused by an input transition pair (HLH or LHL)

= Clock frequency for registered devices, otherwise zero

= Input signal frequency

= Number of inputs changing at f₁

All currents are in milliamperes and all frequencies are in megahertz.

|| Values for these conditions are examples of the I_{CC} formula.



This parameter is derived for use in total power-supply calculations.

 $^{^{\#}}$ IC = ICC + \triangle ICC \times D_H \times N_T + ICCD ($f_0/2 + f_1 \times N_1$)

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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

		CY54FC	T373T	CY54FCT	Y54FCT373AT	
		MIN	MAX	MIN	MAX	UNIT
t _W	Pulse duration, LE high	6		6		ns
t _{su}	Setup time, data before LE↑	2		2		ns
th	Hold time, data after LE↑	1.5		1.5		ns

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

		CY74FCT373T CY74FCT373A		373AT	CY74FCT	373CT	UNIT	
		MIN	MAX	MIN	MAX	MIN	MAX	UNII
t _W	Pulse duration, LE high	6		5		5		ns
t _{su}	Setup time, data before LE↑	2		2		2		ns
th	Hold time, data after LE↑	1.5		1.5		1.5		ns

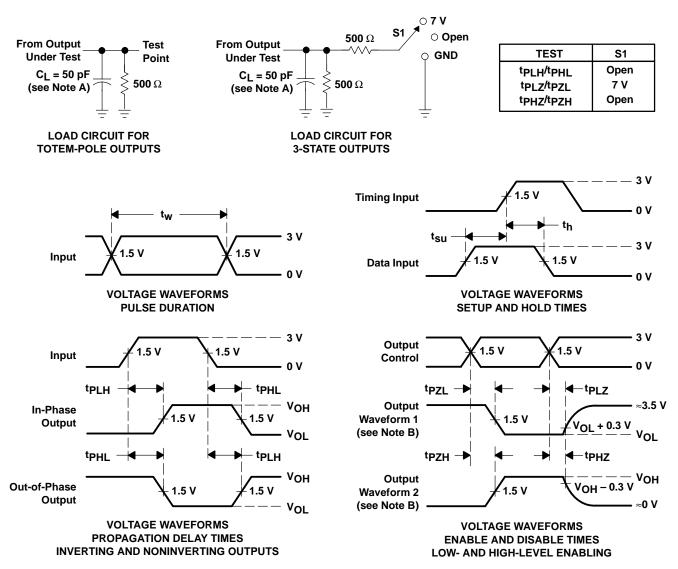
switching characteristics over operating free-air temperature range (see Figure 1)

PARAMETER	FROM	то	CY54FCT	UNIT	
FARAINETER	(INPUT)	(OUTPUT)	MIN	MAX	UNIT
^t PLH	D	0	1.5	5.6	no
^t PHL	Б	0	1.5	5.6	ns
^t PLH	LE	0	2	9.8	ns
^t PHL	LL	O	2	9.8	115
^t PZH	OE	0	1.5	7.5	no
^t PZL	OE	0	1.5	7.5	ns
^t PHZ	ŌĒ	0	1.5	6.5	no
^t PLZ) DE	J	1.5	6.5	ns

switching characteristics over operating free-air temperature range (see Figure 1)

PARAMETER	FROM	то	CY74FC	T373T	CY74FCT	373AT	CY74FCT	373CT	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
t _{PLH}	D	0	1.5	8	1.5	5.2	1.5	4.7	ns
t _{PHL}	U	0	1.5	8	1.5	5.2	1.5	4.7	115
tPLH	LE	0	2	13	2	8.5	2	5.5	20
tpHL		O	2	13	2	8.5	2	5.5	ns
^t PZH	ŌĒ	0	1.5	12	1.5	6.5	1.5	5.5	ns
tpzL	OE	0	1.5	12	1.5	6.5	1.5	5.5	115
^t PHZ	ŌĒ	0	1.5	7.5	1.5	5.5	1.5	5	ns
^t PLZ	OE	O	1.5	7.5	1.5	5.5	1.5	5	115





PARAMETER MEASUREMENT INFORMATION

NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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Mailing Address:

Texas Instruments Post Office Box 655303 Dallas, Texas 75265